

PXP011-20QXJ-VB Datasheet P-Channel 20-V (D-S) MOSFET

PRODUCT SUMMARY						
V _{DS} (V)	$R_{DS(on)}(\Omega)$	I _D (A)	Q _g (Typ.)			
- 20	0.0040 at V _{GS} = 10 V	- 52	21.5 nC			
- 20	0.0060 at V _{GS} = 4.5 V	- 40	21.5110			

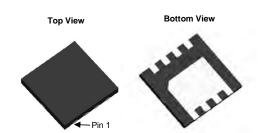
FEATURES

- Halogen-free According to IEC 61249-2-21 Definition
- Trench Power MOSFET
- 100 % R_g Tested
- Compliant to RoHS Directive 2002/95/EC

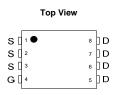


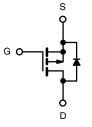
APPLICATIONS

- Load Switch
- · Adaptor/Battery Switch



DFN 3x3 EP





P-Channel MOSFET

ABSOLUTE MAXIMUM RATINGS (T _A = 25 °C, unless otherwise noted)						
Parameter		Symbol	Limit	Unit		
Drain-Source Voltage		V_{DS}	- 20	٧		
Gate-Source Voltage		V _{GS}	± 16	V		
	T _C = 25 °C		- 52			
Continuous Drain Current (T _J = 150 °C)	T _C = 70 °C	I _D	- 40 ^g			
Continuous Diam Current (1) = 150 °C)	T _A = 25 °C	טי	- 26 ^{b, c}			
	T _A = 70 °C		- 21 ^{b, c}	Α		
Pulsed Drain Current	I _{DM}	- 150				
Continuous Source-Drain Diode Current	T _C = 25 °C	I _S	- 40 ^g			
Continuous Course Brain Blode Carrent	T _A = 25 °C	.20	- 4.5 ^{b, c}			
	T _C = 25 °C		54	W		
Maximum Power Dissipation	$T_C = 70 ^{\circ}C$	P _D	34.7			
Waximum Tower Biosipation	T _A = 25 °C	. 0	5.0 ^{b, c}	**		
	T _A = 70 °C		3.2 ^{b, c}			
Operating Junction and Storage Temperature Ran	T _J , T _{stg}	- 55 to 150	°C			
Soldering Recommendations (Peak Temperature)		260	9			

THERMAL RESISTANCE RATINGS						
Parameter		Symbol	Typical	Maximum	Unit	
Maximum Junction-to-Ambient ^{b, f}	t ≤ 10 s	R_{thJA}	20	25	°C/W	
Maximum Junction-to-Case (Drain)	Steady State	R_{thJC}	1.8	2.3	5/ VV	

Notes:

- a. Based on T_C = 25 °C.
- b. Surface Mounted on 1" x 1" FR4 board.
- c. t = 10 s.



Parameter	Symbol	Test Conditions	Min.	Тур.	Max.	Unit	
Static	•						
Drain-Source Breakdown Voltage	V _{DS}	$V_{GS} = 0$, $I_D = -250 \mu A$				V	
V _{DS} Temperature Coefficient	$\Delta V_{DS}/T_{J}$	_{DS} /T _J I _D = - 250 µA		- 15		m\//°C	
V _{GS(th)} Temperature Coefficient	$\Delta V_{GS(th)}/T_J$			4.5		mV/°C	
Gate-Source Threshold Voltage	V _{GS(th)}	$V_{DS} = V_{GS}, I_{D} = -250 \mu A$	- 1		- 2.2	V	
Gate-Source Leakage	I _{GSS}	$V_{DS} = 0 \text{ V}, V_{GS} = \pm 16 \text{ V}$			± 100	nA	
Zarra Cata Valta na Duais Comunat	١,	V _{DS} = - 20 V, V _{GS} = 0 V			- 1	μΑ	
Zero Gate Voltage Drain Current	I _{DSS}	V _{DS} = - 20 V, V _{GS} = 0 V, T _J = 55 °C			- 10		
On-State Drain Current ^a	I _{D(on)}	$V_{DS} \le -5 \text{ V}, V_{GS} = -10 \text{ V}$	- 30			Α	
	В	V _{GS} = - 10 V, I _D = - 26 A	0.0040				
Drain-Source On-State Resistance ^a	R _{DS(on)}	V _{GS} = - 4.5 V, I _D = - 21 A		0.0060		Ω	
Forward Transconductance ^a	9 _{fs}	V _{DS} = - 10 V, I _D = - 26 A		58		S	
Dynamic ^b		,					
Input Capacitance	C _{iss}			4595		pF	
Output Capacitance	C _{oss}	V _{DS} = - 10 V, V _{GS} = 0 V, f = 1 MHz		910			
Reverse Transfer Capacitance	C _{rss}			813			
Total Gate Charge	Qg	V _{DS} = - 10 V, V _{GS} = - 10 V, I _D = - 20 A		95.3	143	nC	
				46.5	70		
Gate-Source Charge	Q_{gs}	$V_{DS} = -10 \text{ V}, V_{GS} = -4.5 \text{ V}, I_{D} = -20 \text{ A}$		13.7			
Gate-Drain Charge	Q_{gd}			12.5			
Gate Resistance	R_g	f = 1 MHz	0.4	1.9	3.8	Ω	
Turn-On Delay Time	t _{d(on)}			19	30		
Rise Time	t _r	V _{DD} = - 10 V, R _L = 1 Ω		10	20	1	
Turn-Off Delay Time	t _{d(off)}	$I_D \cong$ - 10 A, V_{GEN} = - 10 V, R_g = 1 Ω		65	98		
Fall Time	t _f			13	20	ne	
Turn-On Delay Time	t _{d(on)}			55	83	ns -	
Rise Time	t _r	V_{DD} = - 10 V, R_L = 1 Ω		52	78		
Turn-Off Delay Time	t _{d(off)}	$I_D \cong$ - 10 A, V_{GEN} = - 4.5 V, R_g = 1 Ω		53	80		
Fall Time	t _f			25	38		
Drain-Source Body Diode Characteris	tics						
Continuous Source-Drain Diode Current	I _S	T _C = 25 °C			- 40	Δ	
Pulse Diode Forward Current ^a	I _{SM}				- 70	A	
Body Diode Voltage	V_{SD}	I _S = - 1 A		- 0.74	- 1.1	٧	
Body Diode Reverse Recovery Time	t _{rr}			42	63	ns	
Body Diode Reverse Recovery Charge	Q _{rr}	I _F = - 10 A, dl/dt = 100 A/μs, T _{.I} = 25 °C		25	38	nC	
Reverse Recovery Fall Time t _a		$ 1_{\text{F}} = -10 \text{ A}, \text{ al/at} = 100 \text{ A/}\mu\text{s}, 1_{\text{J}} = 25 \text{ °C} $		12			
Reverse Recovery Rise Time	t _b			30		ns	

Notes

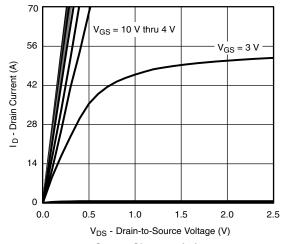
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- a. Pulse test; pulse width $\leq 300~\mu s,$ duty cycle $\leq 2~\%.$
- b. Guaranteed by design, not subject to production testing.

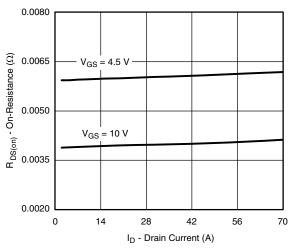
Stresses beyond those listed under "Absolute Maximum Ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated in the operational sections of the specifications is not implied. Exposure to absolute maximum rating conditions for extended periods may affect device reliability.

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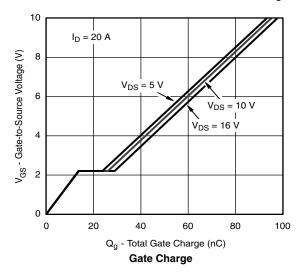


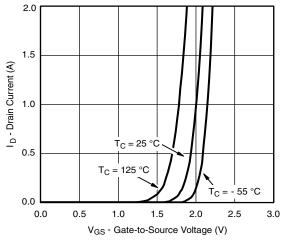


Output Characteristics

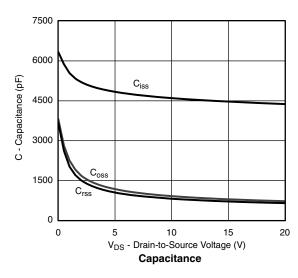


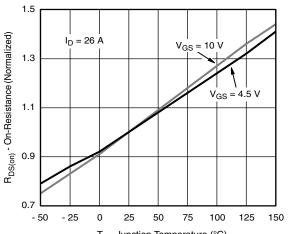
On-Resistance vs. Drain Current and Gate Voltage





Transfer Characteristics

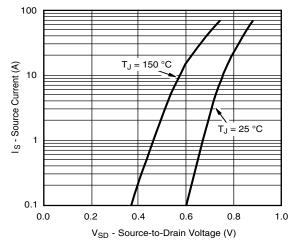


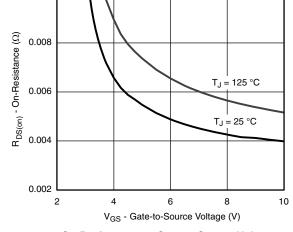


T_J - Junction Temperature (°C)

On-Resistance vs. Junction Temperature



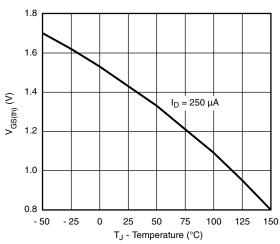


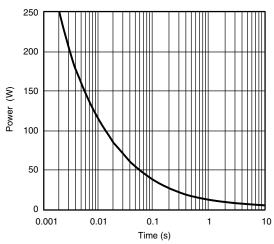


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Source-Drain Diode Forward Voltage

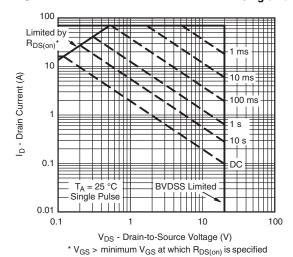






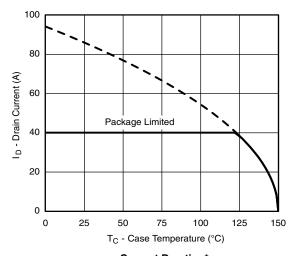
Threshold Voltage

Single Pulse Power, Junction-to-Ambient

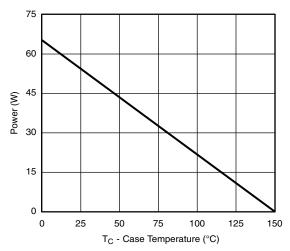


Safe Operating Area, Junction-to-Ambient

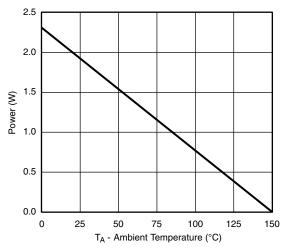




Current Derating*





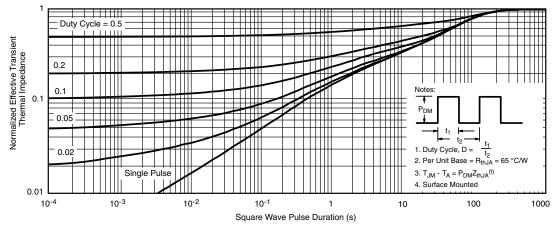


Power, Junction-to-Ambient

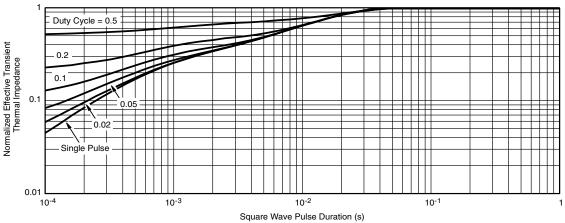
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^{*} The power dissipation P_D is based on $T_{J(max)} = 150$ °C, using junction-to-case thermal resistance, and is more useful in settling the upper dissipation limit for cases where additional heatsinking is used. It is used to determine the current rating, when this rating falls below the package limit.





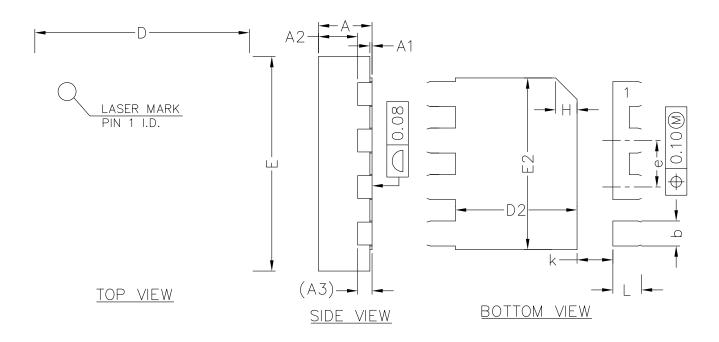
Normalized Thermal Transient Impedance, Junction-to-Ambient



Normalized Thermal Transient Impedance, Junction-to-Case

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COMMON DIMENSIONS (UNITS OF MEASURE=MILLIMETER)

SYMBOL	MIN	NOM	MAX	
А	0.70	0.75	0.80	
A1	0.00	0.02	0.05	
A2	0.50	0.55	0.60	
А3	0.20REF			
b	0.30	0.35	0.40	
D	2.90	3.00	3.10	
Е	2.90	3.00	3.10	
D2	1.60	1.70	1.80	
E2	2.30	2.40	2.50	
е	0.55	0.65	0.75	
K	0.40	0.50	0.60	
L	0.35	0.40	0.45	

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